

IN THE
UNITED STATES PATENT AND TRADEMARK OFFICE

Inventor(s): Jeffrey Paul Witte

Confirmation No.:

Application No.: New Appl.

Examiner:

Filing Date: July 25, 2003

Group Art Unit:

Title: System and Method for Measuring Fault Coverage in an Integrated Circuit

Commissioner for Patents
PO Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

This Information Disclosure Statement is submitted:

- ☒ under 37 CFR 1.97(b), or
(Within three months of filing national application; or date of entry of national application; or before mailing date of first office action on the merits; whichever occurs last)
- ☐ under 37 CFR 1.97(c) together with either a:
() Statement under 37 CFR 1.97(e), or
() a \$180.00 fee under 37 CFR 1.17(p), or
(After the 37 CFR 1.97 (b) time period, but before final action or notice of allowance, whichever occurs first)
- ☐ under 37 CFR 1.97 (d) together with a:
() Statement under 37 CFR 1.97(e)(1) or (2), and
() a \$180.00 fee set forth in 37 CFR 1.17(p).
(Filed after final action, a notice of allowance, on or before payment of the issue fee)

Please charge to Deposit Account **08-2025** the sum of \$0.00. At any time during the pendency of this application, please charge any fees required or credit any overpayment to Deposit Account **08-2025** pursuant to 37 CFR 1.25.

☒ Applicant(s) submit herewith Form PTO 1449 - Information Disclosure Citation together with copies, of patents, publications or other information of which applicant(s) are aware, which applicant(s) believe(s) may be material to the examination of this application and for which there may be a duty to disclose in accordance with 37 CFR 1.56.

☐ A concise explanation of the relevance of foreign language patents, foreign language publications and other foreign language information listed on PTO Form 1449, as presently understood by the individual(s) designated in 37 CFR 1.56 (c) most knowledgeable about the content is given on the attached sheet, or where a foreign language patent is cited in a search report or other action by a foreign patent office in a counterpart foreign application, an English language version of the search report or action which indicates the degree of relevance found by the foreign office is listed on form PTO 1449 and is enclosed herewith.

It is requested that the information disclosed herein be made of record in this application.

"Express Mail" label no. EV331252205US

Date of Deposit July 25, 2003

I hereby certify that this is being deposited with the United States Postal Service "Express Mail Post Office to Addressee" service under 37 CFR 1.10 on the date indicated above and is addressed to: Commissioner for Patents, Washington, D.C. 20231.

By

Shreen K. Danamraj
Typed Name: Shreen K. Danamraj

Respectfully submitted,

Jeffrey Paul Witte

By

Shreen K. Danamraj
Shreen K. Danamraj

Attorney/Agent for Applicant(s)
Reg. No. 41,696

Date: July 25, 2003

PATENT APPLICATION

Sheet 1 of 1

FORM PTO-1449 LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)	ATTY. DOCKET NO. 100201496-2	APPLICATION NO.	CONFIRMATION NO.
	APPLICANT Jeffrey Paul Witt		
	FILING DATE July 25, 2003	GROUP	

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	PUBLICATION DATE	NAME	Pages, Columns, Lines Where Relevant Passages or Figures Appear
	1A	4,716,564	12-29-87	Hung et al.	
	1B	5,189,365	02-23-93	Ikeda et al.	
	1C	5,483,544	01-09-96	Shur	
	1D	5,521,516	05-28-96	Hanagama et al.	
	1E	5,712-857	01-27-98	Whitman et al.	
	1F	5,905,577	05-18-99	Wilsher et al.	
	1G	5,930,588	07-27-99	Paniccia	
	1H	6,059,451	05-09-00	Scott et al.	
	1I	6,072,179	06-06-00	Paniccia et al.	
	1J	6,177,989	01-23-01	Bruce	
	1K				

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	PUBLICATION DATE	NAME OF PATENTEE OR APPLICANT	Pages/Columns/Lines Where Relevant Passages/Figures Appear	Check if Translation attached
	1L					
	1M					
	1N					
	1O					
	1P					

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

1Q	Micaela Serra, Dept. of Computer Science, Univ. of Victoria, Victoria, B.C. Canada; "Digital IC Testing: An Introduction"; undated; 10 pages
1R	
1S	

EXAMINER

DATE CONSIDERED